## SN54LS323, SN74LS323 8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS

CLK SRD

1988

**SDLS160** 

	OCTOBER 1976 - REVISED MARCH
Multiplexed Inputs/Outputs Provide Improved Bit Density	SN54LS323 J OR W PACKAGE SN74LS323 DW OR N PACKAGE (TOP VIEW)
Four Modes of Operation: Hold (Store) Shift Left Shift Right Load Data Operates with Outputs Enabled or at High Z	$\begin{array}{c} SO \left[ 1 \\ \hline 1 \\ \hline 20 \\ \hline V_{CC} \\ \hline G_1 \\ \hline 2 \\ 19 \\ \hline S1 \\ \hline G_2 \\ \hline 3 \\ 18 \\ \hline SL \\ \hline G/QG \\ \hline 4 \\ 17 \\ \hline Q_{QH'} \\ \hline E/QE \\ \hline 5 \\ 16 \\ \hline H/Q_H \\ \hline C/QC \\ \hline 6 \\ 15 \\ \hline E/QF \end{array}$
3-State Outputs Drive Bus Lines Directly Can Be Cascaded for N-Bit Word Lengths Typical Power Dissipation 175 mW	A/QA QA'Q8 13 B8/QB QA'Q8 13 B8/QB CLRQ9 12 CLK GNDQ 10 11 DSR
Exceptionally Stable Shift (Clock) Frequency 25 MHz	SN54LS323 FK PACKAGE (TOP VIEW)
Applications: Stacked or Push-Down Registers, Buffer Storage, and Accumulator Registers	$ \begin{array}{c} 13 & 5 & 3 \\ 3 & 2 & 1 & 20 \\ \hline 3 & 2 & 1 &$
SN54LS299 and SN74LS299 Are Similar But Have Direct Overriding Clear	$ \begin{array}{c} C/Q_{C} = 6 & 16 \\ H/Q_{H} \\ A/Q_{A} = 7 & 15 \\ Q_{A} \neq 8 & 14 \\ 9 = 10 & 11 & 12 & 13 \end{array} $

### description

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These Low-Power Schottky eight-bit universal registers feature multiplexed inputs/outputs to achieve full eight-bit data handling in a single 20-pin package. Two function-select inputs and two output-control inputs can be used to choose the modes of operation listed in the function table. Synchronous parallel loading is accomplished by taking both function-select lines, S0 and S1, high. This places the three-state outputs in a high-impedance state, which permits data that is applied on the input/output lines to be clocked into the register. Reading out of the register can be accomplished while the outputs are enabled in any mode. The clear function is synchronous, and a low level at the clear input clears the register on the next low-to-high transition of the clock.

MODE	INPUTS							INPUTS/OUTPUTS						OUTPUTS				
	CLR	FUNCTION		OUTPUT CONTROL		CLK	SERIAL		A/Q.	8/Qg	c/Qc	0/Qn	E/QE	F/Qs	G/Qc	Н/Он		
		<b>S1</b>	<b>S</b> 0	G1†	G2†	-	SL	SR	ļ .	-	Ŷ		-	•			1 ^	
Clear	L	×	L	Ľ	ι.	t	×	X	L	Ļ	L	ι	L	L	L	Ļ	L	L
	L	ι.	x	L	L	t	×	х	ι	L	L	L	L	L	L	L	L	L
	_L	н	н	x	x	t	X	х	х	х	x	х	x	х	x	×	L	ĩ
Hold	н	L	L	L	L	x	X	X	QAO	QBO	QCO	000	QEO	QFO	QGO	Q <sub>H0</sub>	Q <sub>A0</sub>	ано
	н	×	х	L.	L (	L	X	x	QA0	080	QC0	QD0	QE0	QFO				
Shift Right	н	L	Н	Ł	L	1	X	Ĥ	н	0 <sub>An</sub>		Q <sub>Cn</sub>	Q <sub>Dn</sub>	Q <sub>E</sub> ,	0 <sub>En</sub>	QGo	н	QGn
	н	ίι.	н	L	- L	t	×	L				aça	0 <sub>D0</sub>	0 <sub>En</sub>	QEn	QGn	L	QGn
Shift Left	н	н	L	L	Ĺ	t	м	X	080	ū <sub>Cn</sub>	<sup>Q</sup> Dn	QEn	QEn	QGn	QHn	н	Q <sub>Bn</sub>	H
anni Feit I	н	н	L	L	- L	1	L	X	Q <sub>Bn</sub>	Q <sub>Cn</sub>	۵Du	Q <sub>En</sub>	Q <sub>Fn</sub>	Q <sub>Gn</sub>	Q <sub>Hn</sub>	L	QBn	L
Load	H	н	н	X	X	t	X	X	a	ь	С	d	18	f	9	ħ	a	h

FUNCTION TABLE

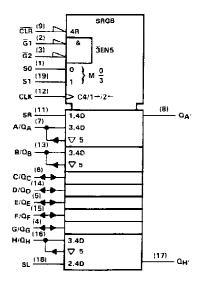
a... h = the level of the steady-state input at inputs A through H, respectively. These data are loaded into the flip-flops while the flip-flop outputs are isolated from the input/output terminals.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all paramaters.



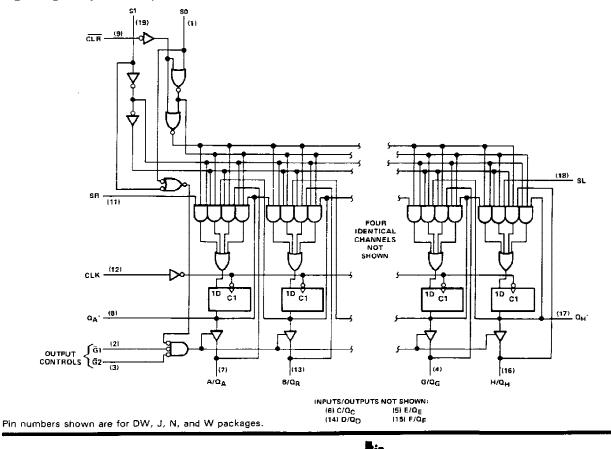
# SN54LS323, SN74LS323 8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS

logic symbol<sup>†</sup>



 $^\dagger This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for DW, J, N, and W packages.$ 

### logic diagram (positive logic)





# schematics of inputs and outputs, absolute maximum ratings, recommended operating conditions, and electrical characteristics

Same as SN54LS299 and SN74LS299, except  $t_{SU}$  (Clear Inactive) does not apply.

### switching characteristics, $V_{CC} = 5 V$ , $T_A = 25^{\circ}C$

PARAMETER <sup>†</sup>	FROM (INPUT)		TEST CONDITIONS	MIN	түр	MAX	UNIT
fmax			See Note 1	25	35		MHz
<sup>t</sup> PLH	CLK Q <sub>A</sub> ' or C	0.1.00.00			22	33	
tphl		UA or UH	$C_{L} = 15  pF, R_{L} = 2  k\Omega$		26	39	ns
<sup>t</sup> PLH	CLK				17	25	
<sup>t</sup> PHL	ULK	Q <sub>A</sub> thru Q <sub>H</sub>			25	39	ns
tPZH	<u> </u>	Q <sub>A</sub> thru Q <sub>H</sub>			14	21	ns
tPZL	<u> </u>				20	30	
tPHZ	<u>Ğ</u> 1, <u>Ğ</u> 2	Q <sub>A</sub> thru Q <sub>H</sub>			10	20	
tPLZ	G, G2		$C_{L} = 5  pF$ , $R_{L} = 665  \Omega$		10	15	ns

<sup>†</sup>t<sub>max</sub> = maximum clock frequency

tPLH = Propagation delay time, low-to-high-level output

tpHL = Propagation delay time, high-to-low-level output

tpzH = Output enable time to high level

tpzL = Output enable time to low level

tpHZ = Output disable time from high level

tpLZ = Output disable time from low level

NOTE 1: For testing f<sub>max</sub>, all outputs are loaded simultaneously, each with C<sub>L</sub> and R<sub>L</sub> as specified for the propagation times. Load circuits and voltage waveforms are shown in Section 1.



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